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Semiconductor devices - Micro-electromechanical devices - Part 20: Gyroscopes

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EN 62047-20

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**Semiconductor devices - Micro-electromechanical devices -
Part 20: Gyroscopes
(IEC 62047-20:2014)**

Dispositifs à semiconducteurs - Dispositifs
microélectromécaniques -
Partie 20: Gyroscopes
(CEI 62047-20:2014)

Halbleiterbauelemente - Bauelemente der
Mikrosystemtechnik -
Teil 20: Gyroskope
(IEC 62047-20:2014)

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The text of document 47F/188/FDIS, future edition 1 of IEC 62047-20, prepared by SC 47F "Microelectromechanical systems" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62047-20:2014.

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IEC 62047-20

Edition 1.0 2014-06

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Semiconductor devices – Micro-electromechanical devices –
Part 20: Gyroscopes**

**Dispositifs à semiconducteurs – Dispositifs microélectromécaniques –
Partie 20: Gyroscopes**



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Edition 1.0 2014-06

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Semiconductor devices – Micro-electromechanical devices –
Part 20: Gyroscopes**

**Dispositifs à semiconducteurs – Dispositifs microélectromécaniques –
Partie 20: Gyroscopes**

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 20: Gyroscopes

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 20: Gyroscopes

1 Scope

This part of IEC 62047 specifies terms and definitions, ratings and characteristics, and measuring methods of gyroscopes.

Gyroscopes are primarily used for consumer, general industries and aerospace applications. MEMS and semiconductor lasers are widely used for device technology of gyroscopes.

Hereafter, gyroscope is referred to as gyro.

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